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** CONTINUING DATA *****
 NONE *AR*

** FOREIGN APPLICATIONS *****
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35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance	Verified and Acknowledged Examiner's Signature <i>AR</i> Initials			

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TITLE
 Photomask defect testing method, photomask manufacturing method and semiconductor integrated circuit manufacturing method

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